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Application/Control No.	Applicant(s)/Patent under Reexamination
10/811,553	LEE ET AL.
Examiner	Art Unit
DUNG A. LE	2818

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EAST, PGPUB, IJPO, EPO TERM SEARCHSEE SEARCH REPORT PRINTOUT.	7/11/2005	DLE
INTERFERENCE SEARCH	7/11/2008	DLE
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